



CLUSTER DETECTOR TEST REPORT

CLUSTER DETECTOR No. 10
Test carried on 08.01.12 – 09.01.12

Ch.	HEX	U _{op} [V]	U _{op} – 500 V		U _{op}			
			FWHM [keV]	$\frac{FWTM}{FWHM}$	1332 keV			122 keV
					FWHM [keV]	$\frac{FWTM}{FWHM}$	Pos. [Ch.]	FWHM [keV]
A	38	4000	2.14	n.c.	2.04	n.c.	6536	
B	56	3500	1.90	n.c.	1.88	n.c.	6520	
C	43	4000	1.96	n.c.	1.85	n.c.	6452	
D	42	4000	2.00	n.c.	1.93	n.c.	6644	
E	37	4000	1.91	n.c.	1.85	n.c.	6586	
F	133	4000	2.05	n.c.	1.97	n.c.	6662	
G	39	3500	2.03	n.c.	1.95	n.c.	6971	

Operational Temperature: -169.9 °C

Date: 09.01.12

Tested by:
/I.kojouharov/

Assembly and test remarks:

Regular test after assembly at RIKEN.

Test Equipment:

HV – ORTEC 660

Main Amplifier – ORTEC 671, $\tau = 6 \mu\text{s}$, Gain 100 x 0.72

ADC – 4801A (RIKEN), MCA - PC98B

Source - ^{60}Co